

54F157A, 54F158A Data Selectors/Multiplexers

54F157A Quad 2-Input Data Selector/Multiplexer (Non-Inverted)
54F158A Quad 2-Input Data Selector/Multiplexer (Inverted)

Military FAST Products

Product Specification

DESCRIPTION

The 54F157A is a high-speed quad 2-input multiplexer which selects 4 bits of data from two sources under the control of a common Select input (S). The Enable input (E) is active Low. When E is High all of the outputs (Y) are forced Low regardless of all other input conditions.

Moving data from two groups of registers to four common output busses is a common use of the 54F157A. The state of the Select input determines the particular register from which the data comes. It can also be used as a function generator. The device is useful for implementing highly irregular logic by generating any four of the 16 different functions of two variables with one variable common.

The device is the logic implementation of a 4-pole, 2-position switch where the position of the switch is determined by the logic levels supplied to the Select input. Logic equations for the outputs are shown below:

$$Y_a = E \cdot (I_{1a} \cdot S + I_{0a} \cdot \bar{S})$$

$$Y_b = E \cdot (I_{1b} \cdot S + I_{0b} \cdot \bar{S})$$

$$Y_c = E \cdot (I_{1c} \cdot S + I_{0c} \cdot \bar{S})$$

$$Y_d = E \cdot (I_{1d} \cdot S + I_{0d} \cdot \bar{S})$$

The 54F158A is similar but has inverting outputs:

$$\bar{Y}_a = E \cdot (I_{1a} \cdot S + I_{0a} \cdot \bar{S})$$

$$\bar{Y}_b = E \cdot (I_{1b} \cdot S + I_{0b} \cdot \bar{S})$$

$$\bar{Y}_c = E \cdot (I_{1c} \cdot S + I_{0c} \cdot \bar{S})$$

$$\bar{Y}_d = E \cdot (I_{1d} \cdot S + I_{0d} \cdot \bar{S})$$

ORDERING INFORMATION

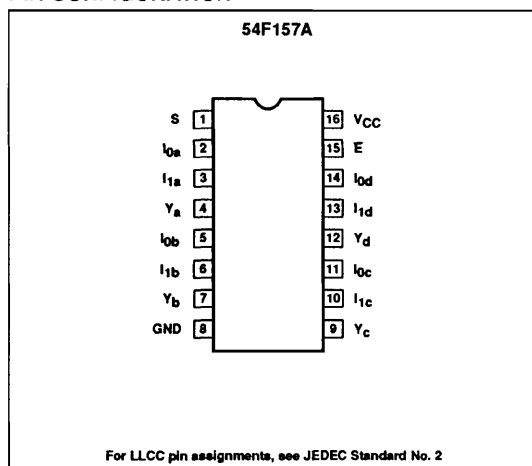
DESCRIPTION	ORDER CODE
16-Pin Ceramic DIP	54F157A/BEA, 54F158A/BEA
16-Pin Ceramic FlatPack	54F157A/BFA, 54F158A/BFA
20-Pin Ceramic LLCC	54F157A/B2A, 54F158A/B2A

INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

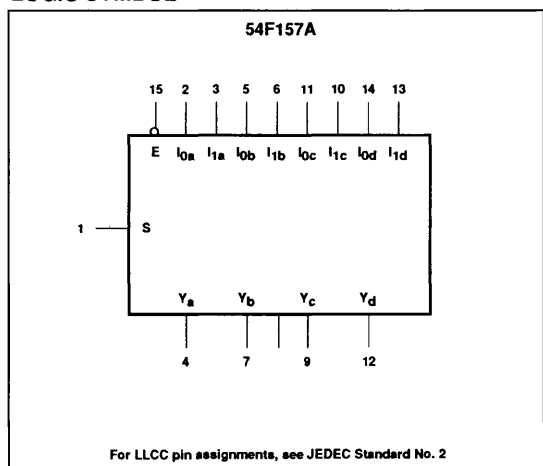
PINS	DESCRIPTION	54F(U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
All	Inputs	1.0/1.0	20μA/0.6mA
$Y_a - Y_d, \bar{Y}_a - \bar{Y}_d$	Outputs	50/33	1.0mA/20mA

NOTE: One (1.0) FAST Unit Load (U.L.) is defined as: 20μA in the High state and 0.6mA in the Low state.

PIN CONFIGURATION



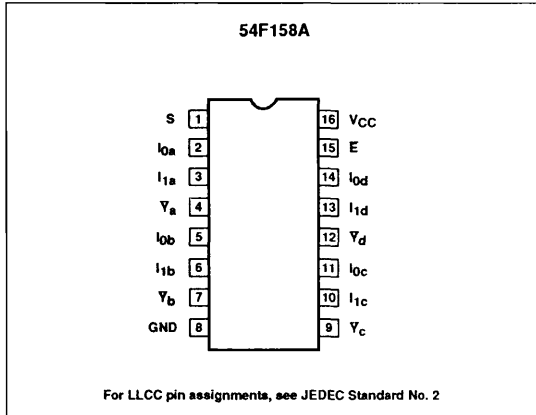
LOGIC SYMBOL



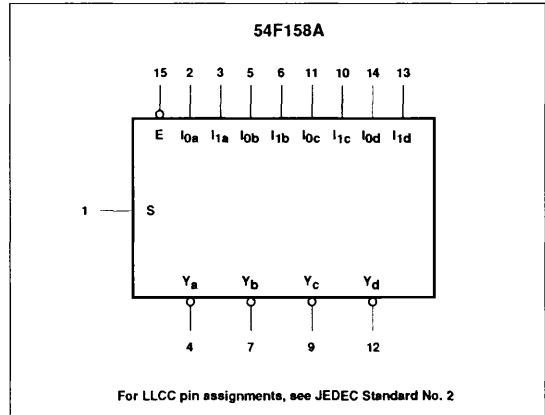
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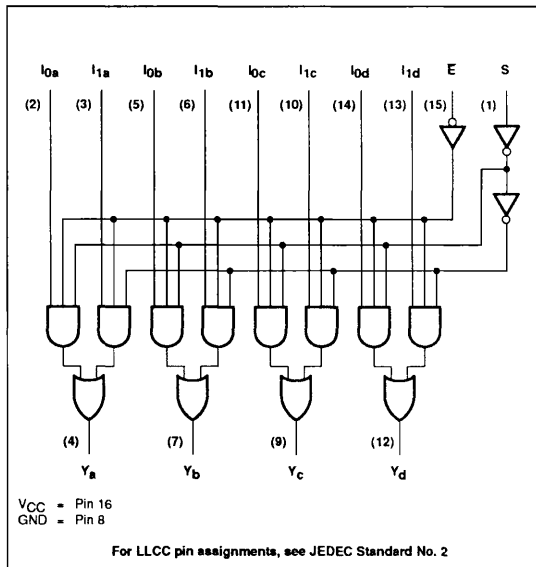
PIN CONFIGURATION



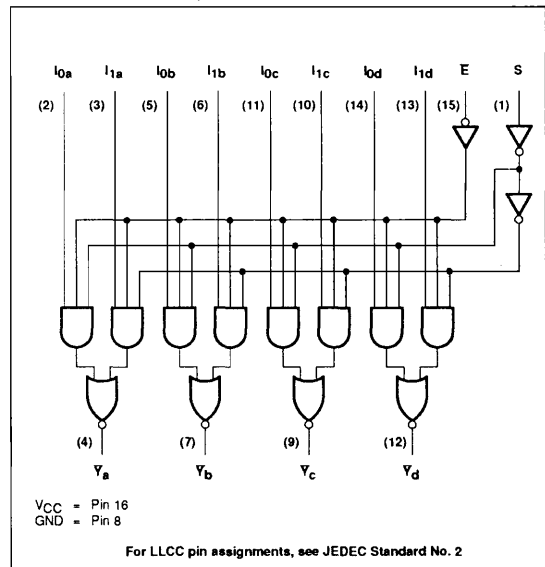
LOGIC SYMBOL



LOGIC DIAGRAM 54F157A



LOGIC DIAGRAM, 54F158A



FUNCTION TABLE, 54F157A

ENABLE	SELECT INPUT	DATA INPUTS		OUTPUT
E	S	I ₀	I ₁	Y
H	X	X	X	L
L	H	X	L	L
L	H	X	H	H
L	L	L	X	L
L	L	L	L	L
L	L	H	X	H

H = High voltage level
 L = Low voltage level
 X = Don't care

FUNCTION TABLE, 54F158A

ENABLE	SELECT INPUT	DATA INPUTS		OUTPUT
E	S	I ₀	I ₁	Y
H	X	X	X	H
L	L	X	X	H
L	L	H	X	L
L	H	X	L	H
L	H	X	H	L
L	L	X	L	L

H = High voltage level
 L = Low voltage level
 X = Don't care

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ABSOLUTE MAXIMUM RATINGS (Operation beyond the limits set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
V _{CC}	Supply voltage range	-0.5 to +7.0	V
V _I	Input voltage range	-0.5 to +7.0	V
I _I	Input current range	-30 to +5	mA
V _O	Voltage applied to output in High output state range	-0.5 to V _{CC}	V
I _O	Current applied to output in Low output state	40	mA
T _{STG}	Storage temperature range	-65 to +150	°C

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS			UNIT
		Min	Nom	Max	
V _{CC}	Supply voltage	4.5	5.0	5.5	V
V _{IH}	High-level input voltage	2.0			V
V _{IL}	Low-level input voltage			+0.8	V
I _{IK}	Input clamp current			-18	mA
I _{OH}	High-level output current			-1	mA
I _{OL}	Low-level output current			20	mA
T _A	Operating free-air temperature range	-55		+125	°C

DC ELECTRICAL CHARACTERISTICS (Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER	TEST CONDITIONS ¹	LIMITS			UNIT
			Min	Typ ²	Max	
V _{OH}	High-level output voltage	V _{CC} = Min, V _{IH} = Min, V _{IL} = Max, I _{OH} = Max	2.5			V
V _{OL}	Low-level output voltage	V _{CC} = Min, V _{IH} = Min, V _{IL} = Max, I _{OL} = Max		0.35	0.50	V
V _{IK}	Input clamp voltage	V _{CC} = Min, I _I = I _{IK}		-0.73	-1.2	V
I _{IH2}	Input current at maximum input voltage	V _{CC} = Max, V _I = 7.0V		5	100	μA
I _{IH1}	High-level input current	V _{CC} = Max, V _I = 2.7V		1	20	μA
I _{IL}	Low-level input current	V _{CC} = Max, V _I = 0.5V		-0.4	-0.6	mA
I _{OS}	Short-circuit output current ³	V _{CC} = Max, V _O = 0.0V	-60	-80	-150	mA
I _{CC}	Supply current ⁴ (total)	'F157A		15.0	23.0	mA
		'F158A		10.0	15.0	mA

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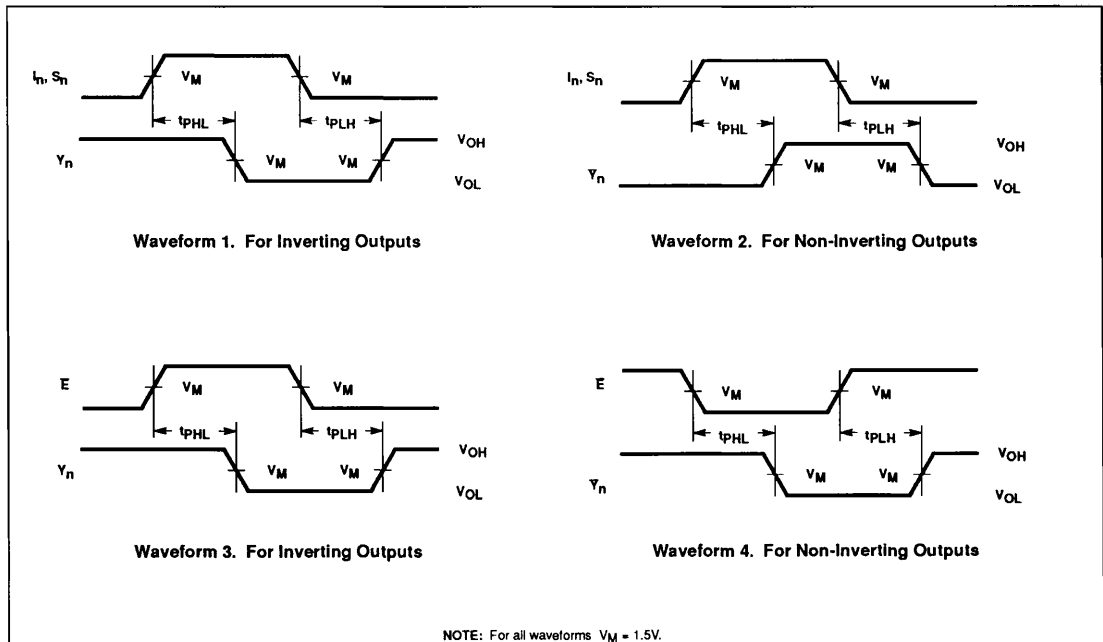
AC ELECTRICAL CHARACTERISTICS (When measured in accordance with the procedures outlined in Signetics LOGIC App Note 202 "Testing and Specifying FAST Logic.")

SYMBOL	PARAMETER	TEST CONDITION	LIMITS					UNIT	
			T _A = +25°C V _{CC} = +5.0V C _L = 50pF, R _L = 500Ω			T _A = -55°C to +125°C V _{CC} = +5.0V ± 10% C _L = 50pF, R _L = 500Ω			
			Min	Typ	Max	Min	Max		
t _{PLH} t _{PHL}	Propagation delay Data to output	'F157A	Waveform 2	3.5 2.5	4.5 3.5	6.5 5.0	2.5 1.5	8.0 7.0	ns ns
t _{PLH} t _{PHL}	Propagation delay Enable to output		Waveform 1	5.0 4.0	7.5 5.0	9.0 6.5	5.0 3.5	12.5 7.5	ns ns
t _{PLH} t _{PHL}	Propagation delay Select to output		Waveform 2	5.5 4.5	7.5 6.0	10.0 7.5	5.0 4.0	12.0 9.5	ns ns
t _{PLH} t _{PHL}	Propagation delay Data to output	'F158A	Waveform 3	3.0 1.5	4.0 2.5	6.0 4.0	2.5 1.0	9.0 5.0	ns ns
t _{PLH} t _{PHL}	Propagation delay Enable to output		Waveform 4	4.0 5.0	5.5 6.0	7.0 7.5	4.0 5.0	8.0 8.5	ns ns
t _{PLH} t _{PHL}	Propagation delay Select to output		Waveform 3	4.5 4.0	6.5 5.5	8.5 7.5	4.0 3.5	12.0 10.0	ns ns

NOTES:

- For conditions shown as Min or Max, use the appropriate value specified under recommended operating conditions for the applicable type and function table for operating mode.
- All typical values are at V_{CC} = 5V, T_A = 25°C.
- Not more than one output should be shorted at a time. For testing I_{OS}, the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.
- I_{CC} is measured with 4.5V applied to all inputs and all outputs open.

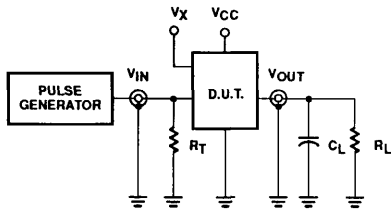
AC WAVEFORMS



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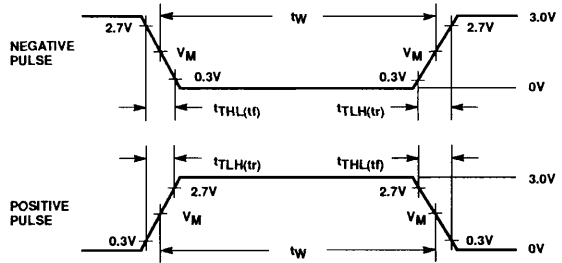
TEST CIRCUIT AND WAVEFORM



Test Circuit for Totem-Pole Outputs

DEFINITIONS:

- R_L = Load Resistor; see AC Characteristics for value.
- C_L = Load capacitance includes jig and probe capacitance; see AC Characteristics for value.
- R_T = Termination resistance should be equal to Z_{OUT} of pulse generators.
- V_X = Unlocked pins must be held at: $\leq 0.8V$; $\geq 2.7V$ or open per Function Table.



$V_M = 1.5V$

Input Pulse Definition

INPUT PULSE CHARACTERISTICS				
Family	Rep. Rate	Pulse Width	t_{TLH}	t_{THL}
54F	1MHz	500ns	$\leq 2.5ns$	$\leq 2.5ns$